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|-----------------------------------|---------------------------------------|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/736,545 | Applicant(s)/Patent Under<br>Reexamination<br>KAWAGUCHI ET AL. |             |
|                                   | Examiner<br>Sue Liu                   | Art Unit<br>1639   | Page 1 of 1 |

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|   | M | US-  |                 |                   |                |

**FOREIGN PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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